



<p style="text-align: center;">Searched</p> 	<p>Application/Control No.</p> <p>10663901</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>KAKUHARI ET AL.</p>
	<p>Examiner</p> <p>Tran, Mai T</p>	<p>Art Unit</p> <p>2129</p>

Class	SubClass	Date	Examiner
706	16	09/12/2006	mtt
29	745, 747, 844, 851, 861	09/12/2006	mtt
72	21.4	09/12/2006	mtt

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Search Notes 	Application/Control No. 10663901	Applicant(s)/Patent Under Reexamination KAKUHARI ET AL.
	Examiner Tran, Mai T	Art Unit 2129

Notes	Date	Examiner
EAST (Please see search history printout)	08/01/2006	mtt
ACM Portal (Please see search history printout)	09/12/2006	mtt
Google (Please see search history printout)	09/12/2006	mtt
IEEE (Please see search history printout)	09/12/2006	mtt
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Interference Searched

Application/Control No.

10663901

Applicant(s)/Patent Under
Reexamination

KAKUHARI ET AL.

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